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(71) Applicant (for all designated States except US): **SAES GETTERS S.P.A.** [IT/IT]; Viale Italia, 77, I-20020 Lainate (IT).

(72) Inventors; and

(75) Inventors/Applicants (for US only): **PUSTERLA, Luca** [IT/IT]; Via Archimede, 42, I-20129 Milano (IT). **SUCCI,**

Marco [IT/IT]; Via Lo Monaco, 9, I-20131 Milano (IT). **BONUCCI, Antonio** [IT/IT]; Via Antonio Cechov 21, I-20151 Milano (IT). **STIMAC, Robert** [US/US]; c/o PCP, Inc., 2155 Indian Road, West Palm Beach, FL 33409-3287 (US).

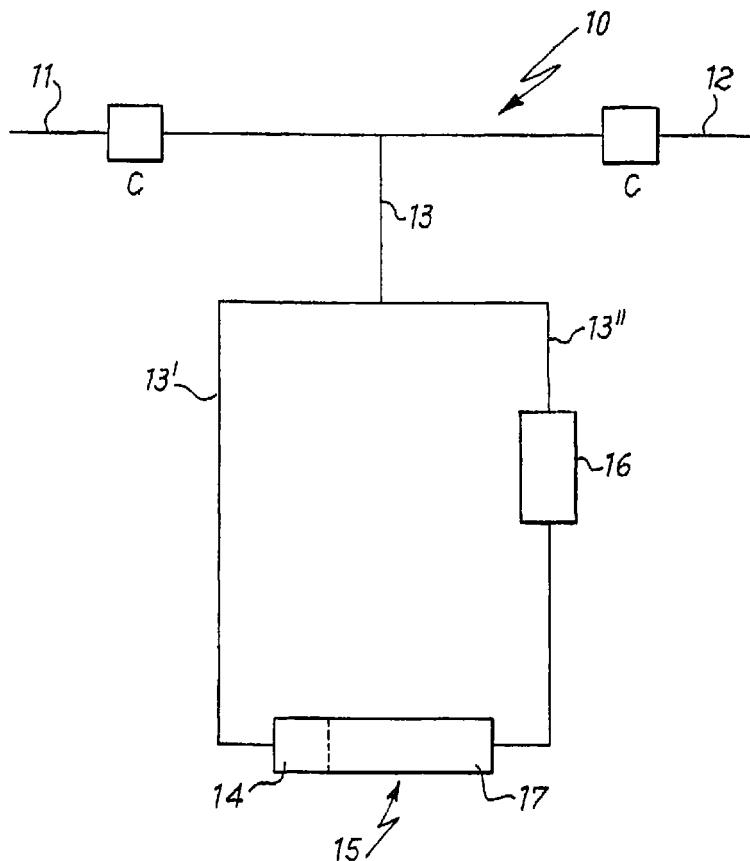
(74) Agents: **ADORNO, Silvano** et al.; Società Italiana Brevetti S.p.A., Via Carducci, 8, I-20123 Milano (IT).

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(57) Abstract: A method for the quantitative analysis of the concentration of impurities in helium by means of ion mobility spectrometry is described, which consists in using purified argon together with the helium which has to be analyzed for forming the sample, or pure argon as counterflow gas in the separation zone of the instrument, or finally helium-purified argon mixtures both for the sample gas and for the counterflow gas.



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